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**ମୁଦ୍ରଣକାରୀ । ଶ୍ରୀ ପିଲାତ୍ତାଳୀ, ପିଲାତ୍ତାଳୀ ମହାନଗର, ଓଡ଼ିଶା ପ୍ରଦେଶ**

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## **Concurrently Herewith**

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## **U.S. PATENT DOCUMENTS**

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING PAPER OR STAPLED IF APPROPRIATE
OVI	5,583,526	12/10/1996	Socks et al.	—	—	
OVI	5,831,584	11/03/1998	Socks et al.	—	—	

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**OTHER DOCUMENTS** (*Including Author, Title, Date, Pertinent Pages, Etc.*)


**EXAMINER**

~~EXAMINER~~  
Albert N. Laino

**ALBERT W. PALADIN**

**DATE CONSIDERED**

2-2-06

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<b>INFORMATION DISCLOSURE CITATION</b> <small>(Use several sheets if necessary)</small>				ATTY DOCKET NO. 200-1453		SERIAL NO. 10/042,918	
				Applicants: Paul J. Stewart et al.		FILING January 11, 2002	
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL	PARENT & TRADE NAME	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<b>RECEIVED</b> <b>SEP 25 2003</b> <b>Technology Center 2100</b>							
<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
<b>OTHER DOCUMENTS</b> <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>							
O VI		Lafon, "Solid Modeling With Constraints and Parameterised Features", IEEE, July 1998.					
		Jinsong et al., "Parametric Design with Intelligence Configuration Analysis Mechanism", IEEE, November 1993.					
GUP		Mateos et al., "Parametric and Associative Design of Cartridges for Special Tools", IEEE 1995.					
EXAMINER <i>Albert W. Paladini</i>		ALBERT W. PALADINI PATENT EXAMINER		DATE CONSIDERED 2-2-86			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

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**Applicants:** Paul J. Stewart et al.

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January 11, 2002

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CMR	5,631,861	05/20/1997	Kramer	—	—	
CWP	5,792,031	08/11/1998	Alton	—	—	
AMY	5,793,382	08/11/1998	Yerazunis et al.	—	—	
CWS	5,831,584	11/03/1998	Socks et al.	—	OCT 28	2003
CM	5,846,086	12/08/1998	Bizzi et al.	Technology	Center 2100	
CWP	5,921,780	07/13/1999	Myers	—	—	
CMW	5,930,155	07/27/1999	Tohi et al.	—	—	
CWJ	5,963,891	10/05/1999	Walker et al.	—	—	
CMW	6,036,345	03/14/2000	Jannette et al.	—	—	
CWM	6,037,945	03/14/2000	Loveland	—	—	
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OCT 28 2003

# Technology Center 2100

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	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

**OTHER DOCUMENTS** (*Including Author, Title, Date, Pertinent Pages, Etc.*)

A ir		<p><b>Artificial Intelligence (Understanding Computers), by Time-Life Books, 1986, ISBN 0-8094-5675-3, pages 36-43.</b></p> <p><b>Juran on Quality by Design, by J.M. Juran, The Free Press, 1992, ISBN 0-02-916683-7, pages 406-427, and 462-467.</b></p> <p><b>The Computer Science and Engineering Handbook, by Allen B. Tucker, CRC Press, ISBN: 0-8493-2909-4, 1996, page 1954.</b></p>

EXAMINER

Att. Mr. Van

ALBERT W. PALADINO  
PATENT EXAMINER

**DATE CONSIDERED**

2-2-06

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## **INFORMATION DISCLOSURE CITATION**

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**Applicants:** Paul J. Stewart et al.

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January 11, 2002

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QW	6,253,167	06/26/2001	Matsuda et al.	—	—	
QY	6,273,724	08/14/2001	Roytman	—	RECEIVED	
MW	2002/0000996 A1	01/03/2002	Trika	—	OCT 28 2003	
GIN	2002/0140633 A1	10/03/2002	Rafil et al.	—	Technology Center 2100	
QW	2003/0134676 A1	07/17/2003	Kang	—	—	

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EXAMINER

*Albert W. Tamm*

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2-2-06

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<b>INFORMATION DISCLOSURE CITATION</b> <small>(Use several sheets if necessary)</small>				ATTY DOCKET NO. 200-1453		SERIAL NO. 10/042,918	
				Applicants: Paul J. Stewart et al.		FILING GROUP January 11, 2002	
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
JM	5,459,382	10/17/1995	Jacobus et al.	—	—		
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JM	6,262,738	07/17/2001	Gibson et al.	—	—		
MH	2002/0133264 A1	09/19/2002	Maiteh et al.	—	—		
CR	2002/0163497 A1	11/07/2002	Cunningham et al.	—	—		
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	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>							
EXAMINER <i>Albert W. Paladini</i>		ALBERT W. PALADINI PATENT EXAMINER	DATE CONSIDERED <i>2-2-06</i>				

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INFORMATION DISCLOSURE CITATION (use several sheets if necessary)			ATTY DOCKET NO. 200-145	SERIAL NO. 10/042,918	
SEP 02 2004			APPLICANT(S) Applicants: Paul J. Stewart et al.		
			FILING DATE January 11, 2002	GROUP 212 2123	
U.S. PATENT DOCUMENTS					
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS
FILING DATE IF APPROPRIATE					
<b>RECEIVED</b> SEP 06 2004 Technology Center 2100					
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Gill			Smid et al., "Human Integration in Simulation" IEEE 1998 pages 554-558. Narinder Nayar, DENER/ERGO--A Simulation-Based Human Factors Tool, 1995, Proceedings of the Winter Simulation Conference, pages 427-431.		
Clay			Deidre L. Donald, "A Tutorial on Ergonomic and Process Modeling Using Quest and IGRIP, 1998, Proceedings of the 1998 Winter Simulation Conference, pages 297-302.		
EXAMINER <i>Albert W. Palmer</i>		ALBERT W. PALMER PATENT EXAMINER	DATE CONSIDERED <i>2-2-02</i>		

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INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)				ATTY DOCKET NO. 200-1453	SERIAL NO. 10/042,918		
				APPLICANT(S) Paul Joseph Stewart et al.			
				FILING DATE January 11, 2002	GROUP 2123		
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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
AM		4,821,214	04/11/1989	Sederberg			
AM		5,119,309	06/02/1992	Cavendish et al.			
AM		5,179,644	01/18/2004	Chiyokura et al.			
AM		5,253,331	10/12/1993	Lorenzen et al.			
AM		5,504,845	04/02/1996	Vecchione			
AM		5,731,816	03/24/1998	Stewart et al.			
AM		5,903,458	05/11/1999	Stewart et al.			
AM		5,999,187	12/07/1999	Dehmlow et al.			
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AM		Duane et al., "DOE/Opt: A System for Design of Experiments, Response Surface Modeling and Optimization Using Process and Device Simulation" 1993. pg.1-4.					
AM		Chen et al., "A Real-Time, Interactive Method for Fast Modification of Large-Scale CAE mesh Models" 2000. pg. 1-8.					
AM		Chen et al. IMF 1.0 User Manual Project No. AJ499 Ford Research Laboratory 10/26/1999. pg.1-14.					
EXAMINER <i>Albert W. Paladino</i>			ALBERT W. PALADINO PATENT EXAMINER		DATE CONSIDERED <i>2-2-06</i>		
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